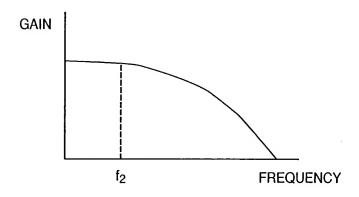
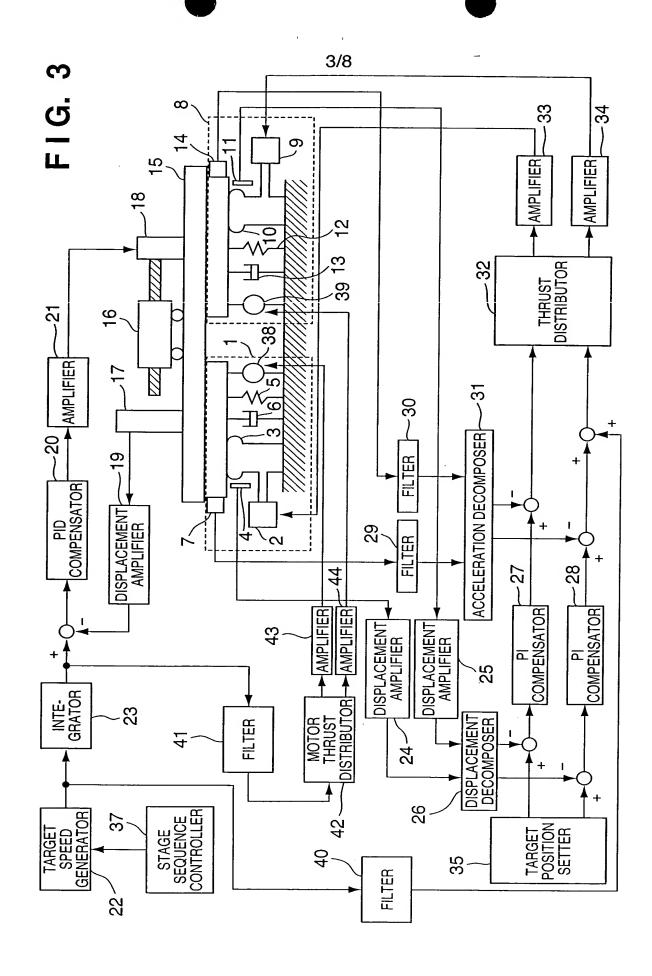
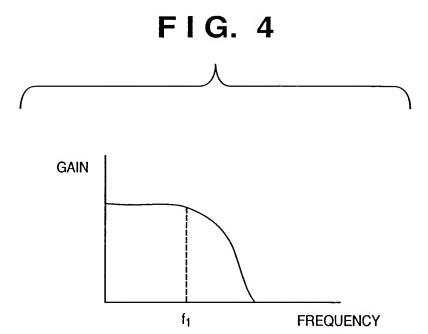


FREQUENCY CHARACTERISTICS OF FILTER 40

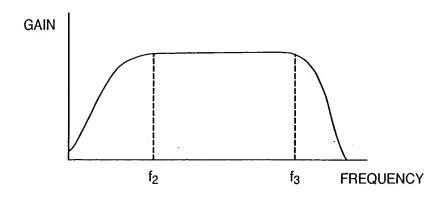


FREQUENCY CHARACTERISTICS OF FILTER 41



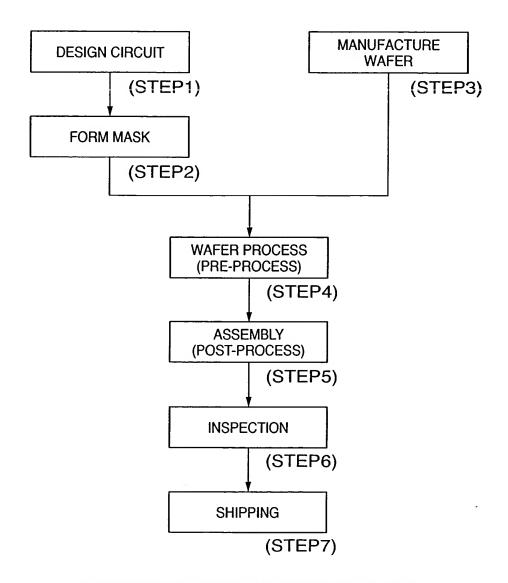


FREQUENCY CHARACTERISTICS OF FILTER 40



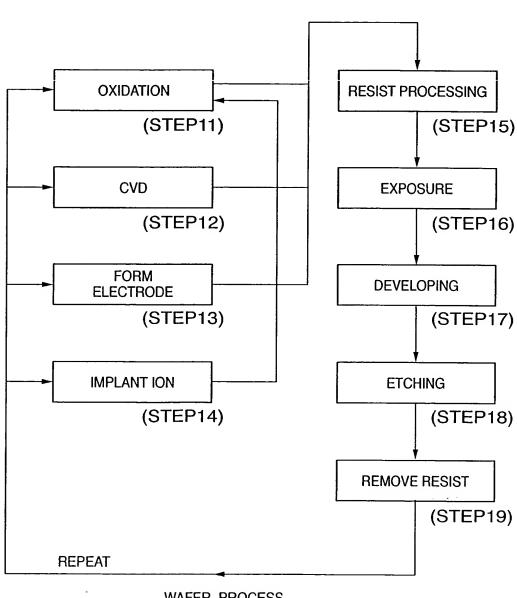
FREQUENCY CHARACTERISTICS OF FILTER 41

FIG. 5



SEMICONDUCTOR DEVICE MANUFACTURING FLOW

FIG. 6



WAFER PROCESS

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